

**Search Notes**

Application/Control No.

10/801,285

Examiner

John Q. Nguyen

Applicant(s)/Patent under  
Reexamination

HANZLIK ET AL.

Art Unit

3654

**SEARCHED**

Class	Subclass	Date	Examiner
242	345 348 610.4 610.6	10/20/2005	JN
360	132	10/20/2005	JN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR